PCN Issue date: 17.11.2026

PCN effective date: 01.03.2027

Products affected: INLT220Q

Change description:

1) Introduction of an additional 200 mm wafer: Identical die fit, form and function.
2) Release of ASE Singapore as an additional Final Test location
3) Product Datasheet Update to revision 1.2 from revision 1.1.

   Updates are listed below:

   Update on section 2.3: Input Voltage Range adapted from 7.5V to 7.8V (Minimum)

   Update on section 6.0: Remove layout example – Detailed explanation provided in Application Note.

   Update on tables 7, 13, 14, 17: See Table below:

Table 7: ISP / ESP R_{Bypass}

	Min	Typ	Max
DS Rev 1.1	85Ω	100Ω	110Ω
DS Rev 1.2	85Ω	100Ω	115Ω

Table 13: Power-on-Reset V_{SUP_POR}

	Min	Typ	Max
DS Rev 1.1	5.6V	6.7V	7.4V
DS Rev 1.2	5.5V	6.7V	7.9V

Table 13: Power-on-Reset V_{CCA_POR}

	Min	Typ	Max
DS Rev 1.1	4.2V	4.4V	4.45V
DS Rev 1.2	4.1V	4.4V	4.5V

Table 14: Undervoltage Lockout ($V_{SUP_UVLO^a}$)

	Min	Typ	Max
DS Rev 1.1	5.5V	6.6V	7.3V
DS Rev 1.2	5.4V	6.6V	7.7V

Table 14: Undervoltage Lockout (V_{SUP_UVLO})

	Min	Typ	Max
DS Rev 1.1	3.0V	3.5V	3.8V
DS Rev 1.2	3.0V	3.5V	3.9V

Table 17: Step Down DC/DC Controller Characteristics			
V_{ref}: Internal Ref. Voltage	**Min**	**Typ**	**Max**
DS Rev 1.1	1.22V	1.25V	1.29V
DS Rev 1.2	1.15V	1.25V	1.35V

Table 17: V_{sense_0V}: Overvoltage Threshold			
	Min	**Typ**	**Max**
DS Rev 1.1	1.27V	1.5V	1.65V
DS Rev 1.2	1.25V	1.5V	1.7V

Table 17: V_{oc} Over-Current Threshold			
	Min	**Typ**	**Max**
DS Rev 1.1	100mV	120mV	150mV
DS Rev 1.2	100mV	120mV	160mV

Reason for change:

1) Dual-source wafer fabrication strategy to increase supply flexibility
2) Dual-source strategy for final testing to increase operational flexibility.
3) Data standardization and harmonization based on the newly collected 200 mm wafer dataset

Impact of change:

1) No negative impact on product's fit, form or function.
2) No negative impact on product's fit, form or function.
3) No negative impact on product's fit, form or function as the changes are limited only to data harmonization.

Traceability:

First date code affected: TBD

Additional Information:

DeQuMa: SEM-PW-02, SEM-PW-13, SEM-TF-01, SEM-DS-01